

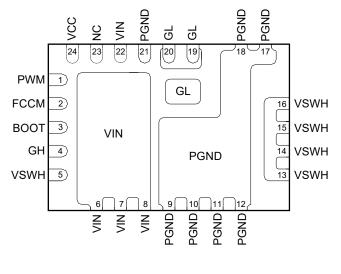
## **Ordering Information**

Part Number	Ambient Temperature Range	Package	Environmental
AOZ5048QI	-40°C to +85°C	QFN3.5x5_24L	RoHS



AOS Green Products use reduced levels of Halogens, and are also RoHS compliant. Please visit www.aosmd.com/media/AOSGreenPolicy.pdf for additional information.

# **Pin Configuration**



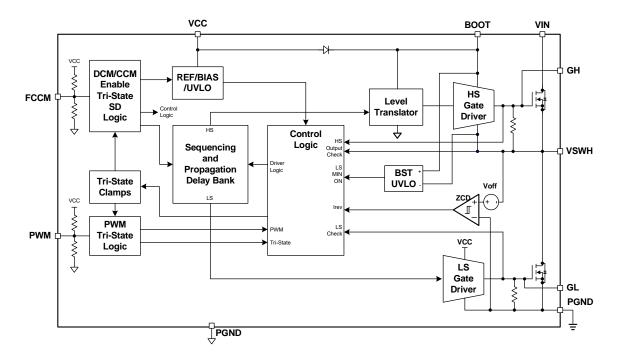
QFN3.5X5\_24L (Top View)



## **Pin Description**

Pin Number	Pin Name	Pin Function
1	PWM	PWM input signal from the controller IC. This input is compatible with 5V and Tri-State logic levels.
2	FCCM	Continuous conduction mode of operation is allowed when FCCM = High. Discontinuous mode is allowed and diode emulation mode is active when FCCM = Low. High impedance on the input of FCCM will shutdown both High Side and Low Side MOSFETs.
3	BOOT	High Side MOSFET Gate Driver supply rail (5V with reference to VSWH). Connect a 100nF ceramic capacitor between BOOT and the VSWH (Pin 5).
4	GH	High Side MOSFET Gate connection. This is for test purposes.
5	VSWH	Switching node connected to the source of High Side MOSFET and the drain of Low Side MOSFET. This pin is dedicated for booststrap capacitor connection to BOOT pin. It is required to be connected to Pin 13 externally on PCB.
6, 7, 8	VIN	Power stage high voltage input pin.
9, 10, 11, 12, 17, 18	PGND	Power Ground pin for power stage.
13, 14, 15, 16	VSWH	Switching node connected to the source of High Side MOSFET and the drain of Low Side MOSFET. These pins are being used for Zero Cross Detect, Booststrap UVLO and Anti-Over- lap Control.
19, 20	GL	Low Side MOSFET Gate connection. This is for test purposes.
21	PGND	Power Ground pin for Low Side MOSFET Gate Driver.
22	VIN	Power stage high voltage input pin.
23	NC	Connect to Pin 24
24	VCC	5V Power Pin for both the Bias Logic Blocks and HS and LS MOSFET Gate Driver Supply Rail. Add a $4.7\mu$ F MLCC directly between Vcc (Pin 24) and PGND (Pin 21).

# **Functional Block Diagram**





## **Absolute Maximum Ratings**

Exceeding the Absolute Maximum ratings may damage the device.

Parameter	Rating
Low Voltage Supply (V <sub>CC</sub> )	-0.3V to 6V
High Voltage Supply (V <sub>IN</sub> )	-0.3V to 30V
Control Inputs (PWM, FCCM)	-0.3V to (V <sub>CC</sub> +0.3V)
Bootstrap Voltage DC (BOOT-PGND)	-0.3V to 33V
Bootstrap Voltage DC (BOOT-VSWH)	-0.3V to 6V
BOOT Voltage Transient <sup>(1)</sup> (BOOT-VSWH)	-0.3V to 9V
Switch Node Voltage DC (VSWH)	-0.3V to 30V
Switch Node Voltage Transient <sup>(1)</sup> (VSWH)	-8V to 38V
High Side Gate Voltage DC (GH)	(VSWH-0.3V) to BOOT
High Side Gate Voltage Transient <sup>(1)</sup> (GH)	(VSWH-5V) to BOOT
Low Side Gate Voltage DC (GL)	(PGND-0.3V) to (V <sub>CC</sub> +0.3V)
Low Side Gate Voltage Transient <sup>(1)</sup> (GL)	(PGND-2.5V) to (V <sub>CC</sub> +0.3V)
Storage Temperature (T <sub>S</sub> )	-65°C to +150°C
Max Junction Temperature (T <sub>J</sub> )	150°C
ESD Rating <sup>(2)</sup>	2kV

#### Notes:

1. Peak voltages can be applied for 20ns per switching cycle.

 Devices are inherently ESD sensitive, handling precautions are required. Human body model rating: 1kΩ in series with 100pF.

## **Recommended Operating Conditions**

The device is not guaranteed to operate beyond the Maximum Recommended Operating Conditions.

Parameter	Rating
High Voltage Supply (V <sub>IN</sub> )	4.5V to 25V
Low Voltage Supply {V <sub>CC</sub> , (BOOT-VSWH)}	4.5V to 5.5V
Control Inputs (PWM, FCCM)	0V to (V <sub>CC</sub> -0.3V)
Operating Frequency	200kHz to 2MHz

# Electrical Characteristics<sup>(3)</sup>

 $T_{A}$  = 25°C,  $V_{IN}$  = 12V,  $V_{CC}$  = 5V unless otherwise specified.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
V <sub>IN</sub>	Power Stage Power Supply		4.5		25	V
V <sub>CC</sub>	Driver Power Supply	$V_{CC} = 5V$	4.5		5.5	V
$R_{ ext{ heta}JC}$	The sum of Designation of	PCB Temp = 100°C		3		°C/W
$R_{ hetaJA}$	Thermal Resistance	AOS Demo Board		10		°C/W
	PLY AND UVLO					
N		V <sub>CC</sub> Rising		3.5	3.9	V
V <sub>CC</sub>	Under-Voltage Lockout	V <sub>CC</sub> Falling		3.1		V
V <sub>CC_HYST</sub>	Under-Voltage Lockout Hysteresis			400		mV
I <sub>VCC_SD</sub>	Shutdown Bias Supply Current	FCCM = Floating. VPWM = Floating (internally pulled down)		3	5	μA
1	Control Circuit Bias Current	FCCM = 5V, VPWM = Floating (internally clamped to 2.5V)		170		μA
I <sub>VCC</sub>		FCCM = 0V, VPWM = Floating (internally clamped to 2.5V)		180		μA
BOOTSTRA	APPED DIODE					
V <sub>F</sub>	Forward Voltage	Forward Current = 2mA		0.55		V
PWM INPU	T	·				
V <sub>PWMH</sub>	PWM Input High Threshold	V <sub>PWM</sub> Rising, V <sub>CC</sub> = 5V	4.1			V
V <sub>PWML</sub>	PWM Input Low Threshold	V <sub>PWM</sub> Falling, V <sub>CC</sub> = 5V			0.7	V
1	DWM Din Innut Current	Source, V <sub>PWM</sub> = 5V		+200		μA
I <sub>PWM</sub>	PWM Pin Input Current	Sink, V <sub>PWM</sub> = 0V		-200		μA
V <sub>TRI</sub>	PWM Input Tri-State Threshold Window	PWM = High Impedance	1.5		3.3	V
FCCM INPL	JT					
V <sub>FCCMH</sub>	FCCM Input High Threshold	FCCM Rising, $V_{CC} = 5V$ Shutdown $\rightarrow$ CCM	3.9			V
V <sub>FCCML</sub>	FCCM Input Low Threshold	FCCM Falling, $V_{CC} = 5V$ Shutdown $\rightarrow$ DCM			1.2	V
Isoou	FCCM Pin Input Current	Source, FCCM = 5V		+50		μA
IFCCM		Sink, FCCM = 0V		-50		μA
V <sub>TRI_HYST</sub>	FCCM Input Threshold Hysteresis	Shutdown $\rightarrow$ CCM $\rightarrow$ Shutdown DCM $\rightarrow$ Shutdown $\rightarrow$ DCM		200		mV
V <sub>TRI</sub>	FCCM Input Tri-State Threshold Window	FCCM = High Impedance, Shutdown Operation	2.1		3.1	V
$V_{TRI\_CMLP}$	Tri-State Open Voltage			2.5		V
t <sub>PS4_EXIT</sub>	PS4 Exit Latency	V <sub>CC</sub> = 5V		5	15	μs
GATE DRIV	/ER TIMING					
t <sub>PDLU</sub>	PWM Falling to GH Turn-Off	PWM 10%, GH 90%		30		ns
t <sub>PDLL</sub>	PWM Raising to GL Turn-Off	PWM 90%, GL 90%		25		ns
t <sub>PDHU</sub>	GL Falling to GH Rising Deadtime	GL 10%, GH 10%		15		ns
t <sub>PDHL</sub>	GH/VSWH Falling to GL Rising Deadtime	VSWH @ 1V, GL 10%		13		ns
t <sub>TSSHD</sub>	Tri-State Shutdown Delay	TS to GH Falling, TS to GL Falling		150		ns
t <sub>PTS</sub>	Tri-State Propagation Delay	Tri-state exit, (see Figure 6)		45		ns
t <sub>LGMIN</sub>	Low-Side Minimum On-Time	FCCM = 0V		350		ns

Note:

3. All voltages are specified with respect to the corresponding PGND pin.



# **Timing Diagram**

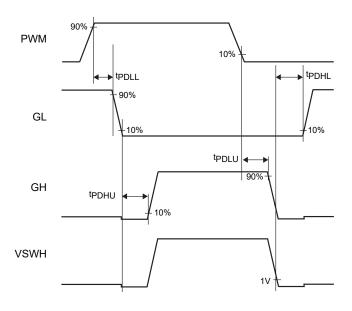


Figure 1. PWM Logic Input Timing Diagram

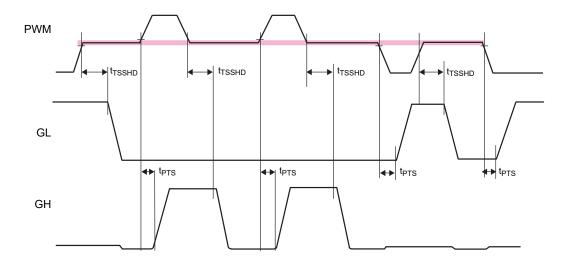


Figure 2. Tri-State Input Logic Timing Diagram



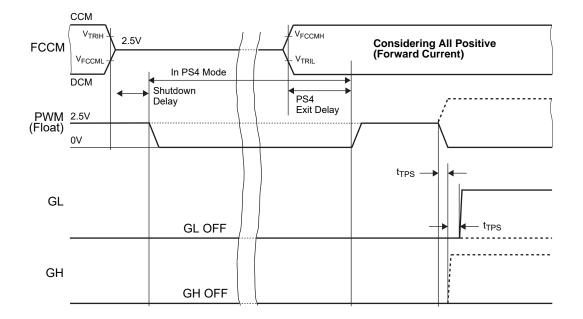


Figure 3. FCCM Logic during High Impedance at PWM Input



# **Typical Performance Characteristics**

 $T_A = 25^{\circ}C$ ,  $V_{IN} = 12V$ ,  $V_{CC} = 5V$ , unless otherwise specified.

## Figure 4. Efficiency vs. Load Current

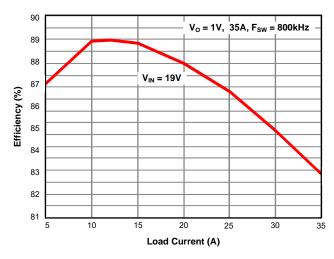


Figure 6. Supply Current vs. Switching Frequency

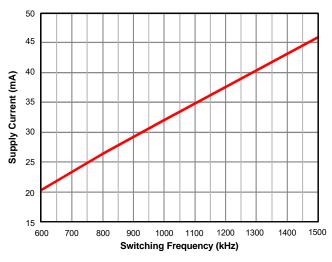


Figure 8. PWM Threshold vs. Temperature

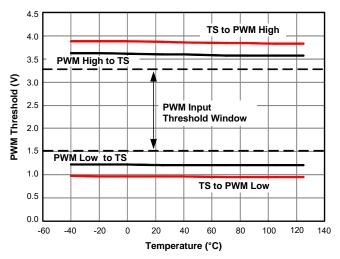


Figure 5. Power Loss vs. Load Current

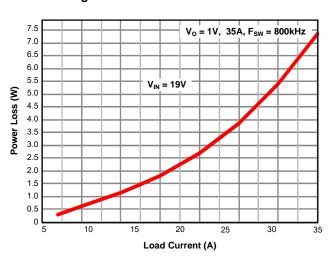


Figure 7. FCCM Input Threshold vs. Temperature

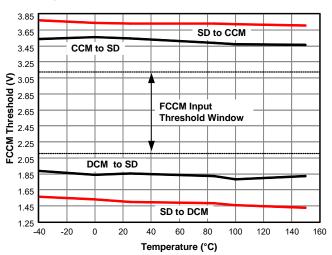
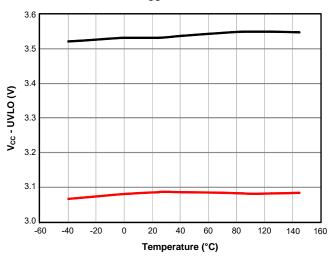


Figure 9. V<sub>CC</sub> UVLO vs. Temperature





# ALPHA & OMEGA

# **Typical Performance Characteristics**

 $T_A$  = 25°C,  $V_{IN}$  = 12V,  $V_{CC}$  = 5V, unless otherwise specified.

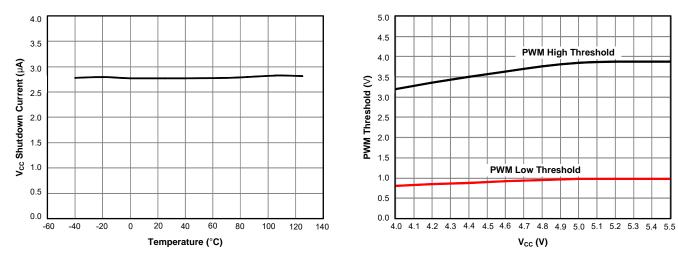
# Figure 10. $V_{\mbox{\scriptsize CC}}$ Shutdown Current vs. Temperature

Figure 11. PWM Threshold vs. V<sub>CC</sub>

PWM Low Threshold

V<sub>cc</sub> (V)

PWM High Threshold





## **Application Information**

AOZ5048QI is a fully integrated power module designed to work over an input voltage range of 4.5V to 25V with a separate 5V supply for gate drive and internal control circuits. A number of desirable features make AOZ5048QI a highly versatile power module. The MOSFETs are individually optimized for efficient operation on either high side or low side switches in a low duty cycle synchronous buck converter. A high current driver is also integrated in the package which minimizes the gate drive loop and results in extremely fast switching The modules are fully compatible with Intel DrMOS specification IMVP8 in form fit and function.

#### Powering the Module and the Gate Drives

An external supply  $V_{CC}$  of 5V is required for driving the MOSFETs. The MOSFETs are designed with low gate thresholds so that lower drive voltage can be used to reduce the switching and drive losses without compromising the conduction losses. The integrated gate driver is capable of supplying large peak current into the Low Side MOSFET to achieve extremely fast switching. A ceramic bypass capacitor of  $4.7\mu$ F or higher is recommended from V<sub>CC</sub> to PGND. For effective filtering it is strongly recommended to directly connect this capacitor to PGND (pin 21).

The BOOT supply for driving the High Side MOSFET is generated by connecting a small capacitor (100nF) between BOOT pin and the switching node VSWH (Pin 5). It is recommended that this capacitor Cboot be connected as close as possible to the device across pins 3 and 5. Boost diode is integrated into the package. A resistor in series with Cboot can be optionally used by designers to slow down the turn on speed of the high side MOSFET. Typically, values between  $1\Omega$  to  $5\Omega$  is a compromise between the need to keep both the switching time and VSWH node spikes as low as possible.

#### **Undervoltage Lockout**

In a UVLO event, both GH and GL outputs are actively held low until adequate gate supply becomes available. The under-voltage lockout is set to 3.5V with a 400mV hysteresis. The AOZ5048QI must be powered up before the PWM input is applied.

Since the PWM control signals are provided typically from an external controller or a digital processor, extra care must be taken during start up. It should be ensured that PWM signal goes through a proper soft start sequence to minimize in-rush current through the converter during start up. Powering the module with a full duty cycle PWM signal may lead to a number of undesirable consequences as explained below. In general it should be noted that AOZ5048QI is a combination of two MOSFETs with an IMVP8 compliant driver, all of which are optimized for switching at the highest efficiency. Other than UVLO, it does not have any monitoring or protection functions built in. The PWM controller should be designed in to perform these functions under all possible operating and transient conditions.

#### Input Voltage V<sub>IN</sub>

AOZ5048QI is rated to operate over a wide input range of 4.5V to 25V. As with any other synchronous buck converter, large pulse currents at high frequency and extremely high di/dt rates will be drawn by the module during normal operation. It is strongly recommended to bypass the input supply very close to package leads with X7R or X5R quality surface mount ceramic capacitors.

The high side MOSFET in AOZ5048QI is optimized for fast switching with low duty ratios. It has ultra low gate charges which have been achieved as a trade off with higher RDS(ON) value. When the module is operated at low V<sub>IN</sub> the duty ratio will be higher and conduction losses in the HS MOSFET will also be correspondingly higher. This will be compensated to some extent by reduced switching losses. The total power loss in the module may appear to be low even though in reality the HS MOSFET losses may be disproportionately high. Since the two MOSFETs have their own exposed pads and PCB copper areas for heat dissipation, the HS MOSFET may be much hotter than the LS MOSFET. It is recommended that worst case junction temperature be measured and ensured to be within safe limits when the module is operated with high duty ratios.

#### **PWM Input**

AOZ5048QI is offered to interface with PWM logic compatible with 5V (TTL). Refer to Fig. 1 for the timing and propagation delays between the PWM input and the gate drives.

The PWM is also a tri-state compatible input. When the input is high impedance or unconnected both the gate drives will be off and the gates are held active low. The PWM Threshold Table in Table 1 lists the thresholds for high and low level transitions as well as tri-state operation. As shown in Fig. 2, there is a hold off delay between the corresponding gate drive is pulled low. This delay is typically 150ns and intended to prevent spurious triggering of the tri-state mode which may be caused either by noise induced glitches in the PWM waveform or slow rise and fall times.

#### Table 1. PWM Input and Tri-State Thresholds

Thresholds $\rightarrow$	V <sub>PWMH</sub>	V <sub>PWML</sub>	V <sub>TRIH</sub>	V <sub>TRIL</sub>
AOZ5048QI	4.1 V	0.7 V	1.65 V	3.50 V

Note: See Figure 2 for propagation delays and tri-state window.

#### Diode Mode Emulation of Low Side MOSFET (FCCM)

AOZ5048QI can be operated in the diode emulation or skip mode using the FCCM pin. This is useful if the converter has to operate in asynchronous mode during start up, light load or under pre bias conditions. If FCCM is taken high, the controller will use the PWM signal as reference and generate both the high and low side complementary gate drive outputs with the minimal delays necessary to avoid cross conduction. When the pin is taken low the HS MOSFET drive is not affected but diode emulation mode is activated for the LS MOSFET. See Table 2 for a comprehensive view of all logic inputs and corresponding drive conditions. A high impedance state at the FCCM pin shuts down the AOZ5048QI.

#### Function of FCCM When Signal is Rising

#### FCCM = 0V

- 1. The power stage is enabled and in DCM (Discontinuous Conduction Mode).
- 2. GH and GL will follow PWM signal
- 3. Zero Current Detection (ZCD) is enabled. When VSWH = 4mV and MIN\_ON expires, ZCD will trigger state machine to turn off GL. If VSWH reaches 4mV before than MIN\_ON, MIN\_ON time takes priority and will continue until this time period has completed.

#### FCCM = 0V to 2.1V

1. GH and GL will turn off after shutdown delay (2.5µs).

#### FCCM = Tri-State Window

- 1. Input to FCCM is high impedance.
- 2. An internal buffer clamps FCCM to 2.5V.
- 3. GH and GL remain Off and ignore PWM signal.

#### FCCM = Tri-State to 3.9V (Fast Ramping)

- 1. The power stage is in CCM (Continuous Conduction Mode)
- 2. GH and GL will follow PWM command
- 3. ZCD: is disabled

### FCCM = 5V

- 1. The power stage is in CCM (Continuous Mode of Operation)
- 2. Zero Current Detection (ZCD) is disabled

3. GH and GL follow PWM signal:

PWM = Logic Hi  $\rightarrow$  GH = Hi, GL = Lo

PWM = Logic Lo  $\rightarrow$  GH = Lo, GL = Hi

- 4. No detection for direction of inductor current
- 5. No detection for Voltage Level at VSWH node

# Function of FCCM When Signal is Falling FCCM = $5V \rightarrow 3.1V$

- 1. Re-enter shutdown mode
- 2. Shutdown delay: 2.5µs
- 3. Occurs when Controller FCCM output enter high impedance state

#### FCCM = Tri-State Window

#### (Ramp down window is 3.1 to 1.2V)

- 1. FCCM will be internally clamped to 2.5V
- 2. Remains in Shutdown Mode

#### $\textbf{FCCM} = \textbf{Tri-State} \rightarrow \textbf{1.2V}$

#### (250 to 300mV lower than the DCM $\rightarrow$ TS threshold)

- 1. Re-enable power stage
- 2. Controller pulls down on FCCM pin exiting shutdown mode into DCM
- 3. Enable Delay: 5µs
- 4. Re-enable ZCD

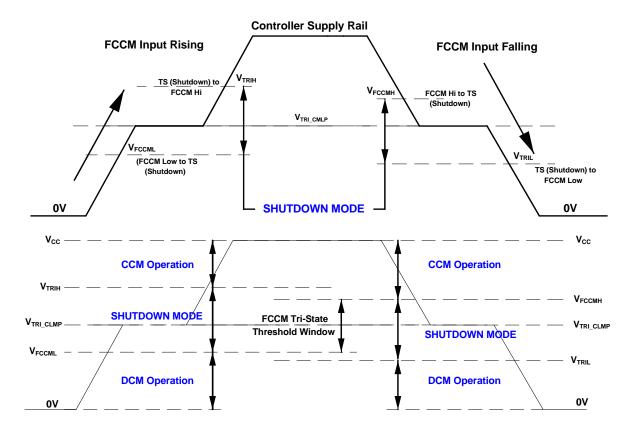
#### Table 2. Control Logic Truth Table

FCCM	PWM	GH	GL		
L	L	L	L (ZCD)		
L	Н	H H L			
Н	L	L	Н		
Н	Н	Н	L		
L	Tri-State	L	L		
Н	Tri-State L		L		
Tri-State	Х	L	L		

Note: Diode emulation mode is activated when FCCM pin is held low.



## **FCCM Timing Diagram and Truth Table**

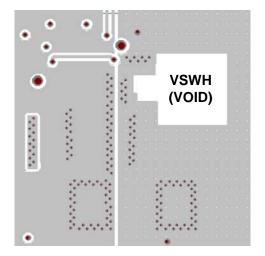


FCCM	ZCD	PWM	VSWH	GH	GL	Main Inductor Current Direction
0V		L	<-4mV	L	L	Forward Current
0V	ON	L	Equal -4mV	L	MinOn Time	VSWH= -(Rdson x IL <sub>FORWARD</sub> )
0V	ON	Tri-S	V <sub>OUT</sub>	L	L	Don't Care
0V		Н	V <sub>IN</sub>	Н	L	Forward Only
5V		L	Х	L	Н	Bi-Directional
5V	OFF	Tri-S	V <sub>OUT</sub>	L	L	Forward (Body)
5V	OFF	Н	V <sub>IN</sub>	Н	L	Bi-Directional
Tri-State		Х	V <sub>OUT</sub>	L	L	Don't Care



As the primary and secondary AC current loops move through  $V_{IN}$  to VSWH and through PGND to VSWH, large positive and negative voltage spike appear at the VSWH terminal which are caused by the large internal di/ dts produced through the in package parastics. To minimize the effects of this interference, the VSWH terminal at which the main inductor L1 is mounted to, is sized just so the inductor can physically fit. The goal is to employ the least amount of copper area for this VSWH terminal just enough so the inductor can be securely mounted.

To minimize the effects of switching noise coupling to the rest of the sensitive areas of the PCB, the area directly underneath the designated VSWH copper plane on the top layer is voided and the shape of this void is replicated descending down through the rest of the layers as shown on Fig. 14 which is the bottom layer of the PCB as an example.



# Figure 14. Bottom Layer PCB Layout with VSWH Copper Plane Voided on Descending Layers

The AOZ5048QI can be operated at a switching frequency of up to 1.5MHz. This implies that the inherent capacitive parameters of the High Side and Low Side MOSFETs need to be charged and discharge on each and every cycle. Due to the back and forth conduction of these AC currents flowing in and out of the Input Capacitors, the exposed pads ( $V_{IN}$  and PGND) would tend to heat up, hence requiring thermal venting.

Positioning vias through the landing pattern of the  $V_{IN}$  and PGND thermal pads will help quickly facilitate the thermal build up and spread the heat much more quickly towards the surrounding copper layers descending from the top layer.

The exposed pads dimensional footprint of the 3.5x5 QFN package is shown on Fig.13. For optimal thermal relief, it is recommended to fill the PGND and  $V_{\rm IN}$  exposed landing pattern with 10mil diameter vias.

10mil diameter is a commonly used via diameter as it is optimally cost effective based on the tooling bit used in manufacturing. Each via is associated with a 20mil diameter keep out. Maintain a 5mil clearance (127um) around the inside edge of each exposed pad in an event of solder overflow, potentially shorting with the adjacent expose thermal pad.

#### Adding Vias Through Exposed Pads Landing Pattern

The AOZ5048QI can be operated at a switching frequency of up to 1.5MHz. This implies that the inherent capacitive parameters of the High Side and Low Side MOSFETs need to be charged and discharged on each and every cycle. Due to the back and forth conduction of these AC currents flowing in and out of the Input Capacitors, the exposed pads ( $V_{IN}$  and PGND) would tend to heat up, hence requiring thermal venting. Positioning vias through the landing pattern of the  $V_{IN}$  and PGND thermal pads will help quickly facilitate the thermal build up and spread the heat much more quickly towards the surrounding copper layers descending from the top layer.

The exposed pads dimensional footprint of the 3.5x5 QFN package is shown on Fig.15. For optimal thermal relief, it is recommended to fill the PGND and  $V_{\rm IN}$  exposed landing pattern with 10mil diameter vias. 10mil via diameter is a commonly used, as it is optimally cost effective based on the tooling bit used in manufacturing. Each via is associated with a 20mil diameter keep out. Maintain a 5mil clearance (127um) around the inside edge of each exposed pad in an event of solder overflow, potentially shorting with the adjacent expose thermal pad.



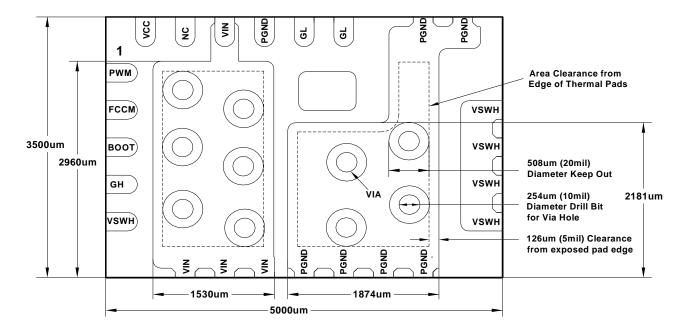
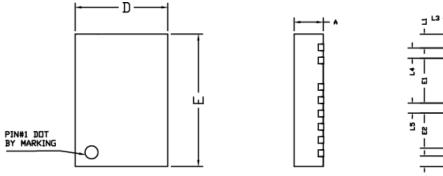
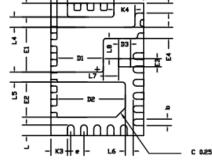


Figure 15. Exposed Pad Land Pattern and Recommended Via Placements

# Package Dimensions, QFN3.5x5A\_24L





L2

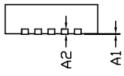
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TOP VIEW

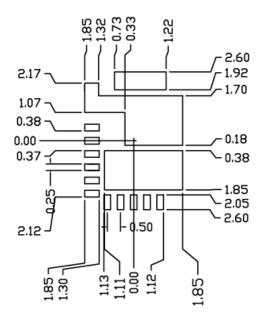
SIDE VIEW

BOTTOM VIEW



SIDE VIEW

## RECOMMENDED LAND PATTERN



0.440.01.0	DIM	ENSION IN	MM	DIMENSION IN INCHES			
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
A	1.00	1.10	1.20	0.039	0.043	0.047	
A1	0.00	-	0.05	0.000	-	0.002	
A2		0.2REF			0.008REF		
E	4.90	5.00	5.10	0.193	0.197	0.201	
E1	1.66	1.71	1.76	0.065	0.067	0.069	
E2	1.27	1.32	1.37	0.050	0.052	0.054	
E3	0.25	0.30	0.35	0.010	0.012	0.014	
E4	0.38	0.43	0.48	0.015	0.017	0.019	
D	3.40	3.50	3.60	0.134	0.138	0.142	
D1	1.70	1.75	1.80	0.067	0.069	0.071	
D2	2.53	2.58	2.63	0.100	0.102	0.104	
D3	0.40	0.45	0.50	0.016	0.018	0.020	
L	0.35	0.40	0.45	0.014	0.016	0.018	
L1	0.48	0.53	0.58	0.019	0.021	0.023	
L2	1.70	1.75	1.80	0.067	0.069	0.071	
L3	0.18	0.23	0.28	0.007	0.009	0.011	
L4	0.32	0.37	0.42	0.013	0.015	0.017	
L5	0.33	0.38	0.43	0.013	0.015	0.017	
L6	0.25	0.30	0.35	0.010	0.012	0.014	
L7	0.53	0.58	0.63	0.021	0.023	0.025	
L8	0.72	0.77	0.82	0.028	0.030	0.032	
K1	1.08	1.13	1.18	0.042	0.044	0.046	
K2	0.33	0.38	0.43	0.013	0.015	0.017	
К3	0.58	0.63	0.68	0.023	0.025	0.027	
K4	0.75	0.80	0.85	0.030	0.031	0.033	
b	0.20	0.25	0.30	0.008	0.010	0.012	
e		0.50BSC			0.02BSC		

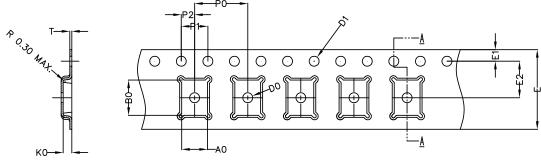
UNIT: mm

NOTE CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



## Tape and Reel Dimensions, QFN\_3.5x5\_24L\_EPS\_2

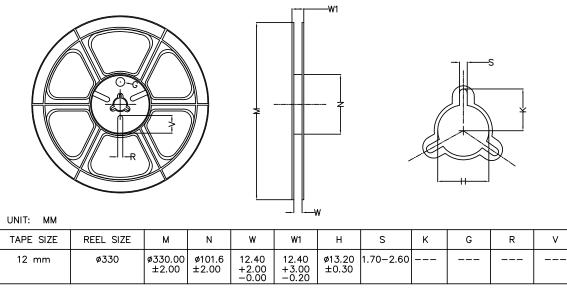
### **Carrier Tape**



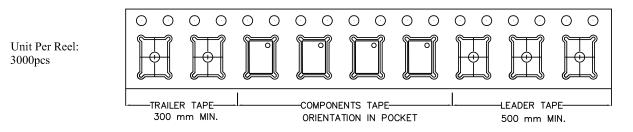
FFFDING	DIRECTION

UNIT: MM												
PACKAGE	AO	BO	ко	DO	D1	Е	E1	E2	PO	P1	P2	Т
QFN3.5x5 (12 mm)	3.89 ±0.10	5.31 ±0.10	1.30 ±0.10	1.50 MIN.	1.50 +0.10 0.00	12.00 ±0.30	1.75 ±0.10	5.50 ±0.05	8.00 ±0.10	4.00 ±0.10	2.00 ±0.05	0.30 ±0.05

Reel

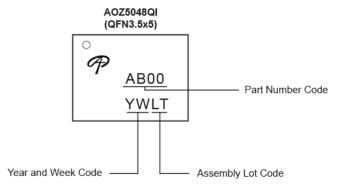


## Leader / Trailer & Orientation





## **Part Marking**



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